

December 2007

# FDMS5672 N-Channel UltraFET Trench $^{(\!R\!)}$ MOSFET 60V, 22A, 11.5m $_{\Omega}$

#### **Features**

- Max  $r_{DS(on)}$  = 11.5m $\Omega$  at  $V_{GS}$  = 10V,  $I_D$  = 10.6A
- Max  $r_{DS(on)}$  = 16.5m $\Omega$  at  $V_{GS}$  = 6V,  $I_D$  = 8A
- Typ Qg = 32nC at V<sub>GS</sub> = 10V
- Low Miller Charge
- Optimized efficiency at high frequencies
- RoHS Compliant

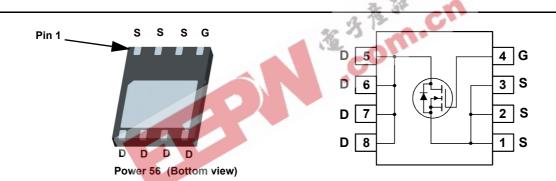


## **General Description**

UltraFET devices combine characteristics that enable benchmark efficiency in power conversion applications. Optimized for  $r_{DS(on)}$ , low ESR, low total and Miller gate charge, these devices are ideal for high frequency DC to DC converters.

## **Application**

■ DC - DC Conversion



## MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
$V_{DS}$	Drain to Source Voltage			60	V
$V_{GS}$	Gate to Source Voltage			±20	V
I <sub>D</sub>	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25°C		22	
	-Continuous (Silicon limited) T <sub>C</sub> = 25°C		65	_	
	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	10.6	Α
	-Pulsed			60	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	337	mJ
В	Power Dissipation	T <sub>C</sub> = 25°C		78	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	2.5	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

## **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS5672	FDMS5672	Power 56	13"	12mm	3000 units

# Electrical Characteristics T<sub>J</sub> = 25°C unless otherwise noted **Parameter**

Off Characteristics							
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	60			V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, referenced to 25°C		59		mV/°C	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 48V, V <sub>GS</sub> = 0V			1	μА	
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA	

**Test Conditions** 

Min

Тур

Max

Units

## **On Characteristics**

**Symbol** 

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	3.2	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C		-11		mV/°C
	Drain to Source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 10.6A		9.4	11.5	
r		$V_{GS} = 6V$ , $I_D = 8A$		13.0	16.5	mΩ
r <sub>DS(on)</sub> Drain to Source On Resistance		$V_{GS} = 10V, I_D = 10.6A,$ $T_J = 125^{\circ}C$		15.0	18.0	11122
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10V, I <sub>D</sub> = 10.6A		26		S

## **Dynamic Characteristics**

9FS	I diward Transconductance	VDS - 10 V, 1D - 10.0A	20		
Dynami	c Characteristics	4.47			
C <sub>iss</sub>	Input Capacitance	V = 20V V = 0V	2100	2800	pF
Coss	Output Capacitance	$V_{DS} = 30V, V_{GS} = 0V,$ f = 1MHz	375	500	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	10112	120	180	pF
$R_{\alpha}$	Gate Resistance	f = 1MHz	1.2		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		16	29	ns
t <sub>r</sub>		$V_{DD} = 30V, I_{D} = 10.6A$	17	31	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10V, $R_{GEN}$ = $6\Omega$	22	35	ns
t <sub>f</sub>	Fall Time		8	16	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	V <sub>GS</sub> = 0V to 10V	32	45	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DD} = 30V$ $I_{D} = 10.6A$	10		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	ID - 10.0A	8.3		nC

#### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 10.6A (Note 2)		0.80	1.20	V
t <sub>rr</sub>	Reverse Recovery Time	L = 10.64 di/dt = 1004/		35	53	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 10.6A, di/dt = 100A/μs		42	63	nC

#### Notes:

1: R<sub>0JA</sub> is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a. 50°C/W when mounted on a 1 in² pad of 2 oz copper



b. 125°C/W when mounted on a minimum pad of 2 oz copper

- 2: Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%. 3: Starting T $_J$  = 25°C, L = 3mH, I $_{AS}$  = 15A, V $_{DD}$  = 60V, V $_{GS}$  = 10V.

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

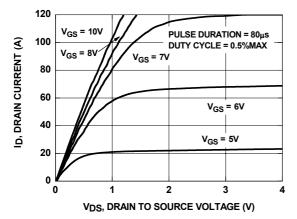


Figure 1. On Region Characteristics

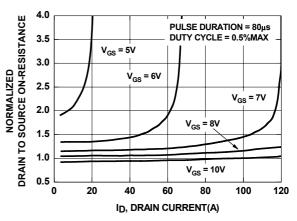


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

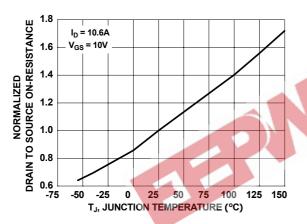


Figure 3. Normalized On Resistance vs Junction Temperature

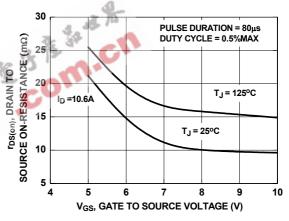


Figure 4. On-Resistance vs Gate to Source Voltage

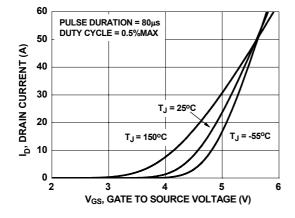


Figure 5. Transfer Characteristics

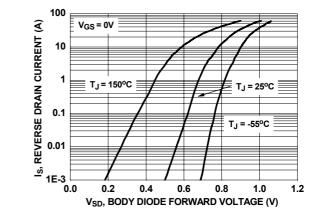


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

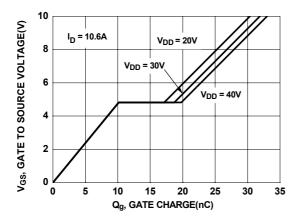


Figure 7. Gate Charge Characteristics

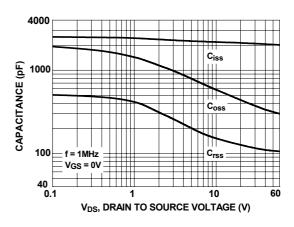


Figure 8. Capacitance vs Drain to Source Voltage

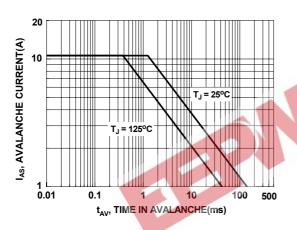


Figure 9. Unclamped Inductive Switching Capability

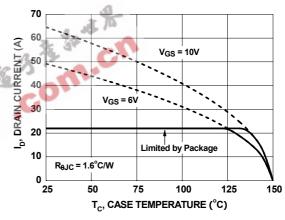


Figure 10. Maximum Continuous Drain Current vs Case Temperature

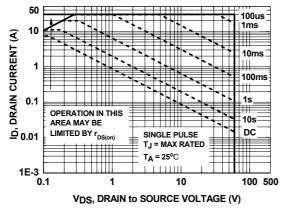


Figure 11. Forward Bias Safe Operating Area

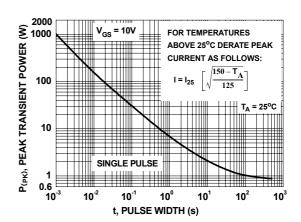


Figure 12. Single Pulse Maximum Power Dissipation



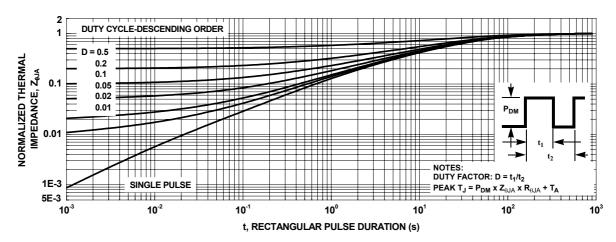
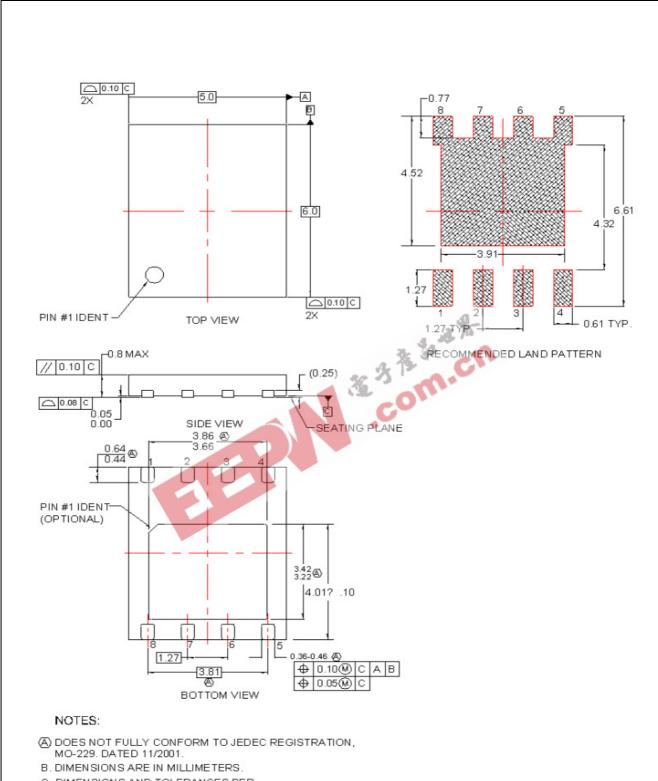


Figure 13. Transient Thermal Response Curve





- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. TERMINALS 5,6,7 AND 8 ARE TIED TO THE EXPOSED PADDLE

#### MLP08GrevD





#### **TRADEMARKS**

The following are registered and unregistered trademarks and service marks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx<sup>®</sup>
Build it Now™
CorePLUS™
CROSSVOLT™
CTL™

Current Transfer Logic™ EcoSPARK® EZSWITCH™ \*

Reference of the second second

Fairchild Semiconductor<sup>®</sup>
FACT Quiet Series<sup>™</sup>
FACT<sup>®</sup>

FAST<sup>®</sup>
FastvCore™
FlashWriter<sup>®</sup> \*

FPS™ FRFET®

Global Power Resource<sup>SM</sup>

Green FPS™

Green FPS™ e-Series™

GTO™
i-Lo™
IntelliMAX™
ISOPLANAR™
MegaBuck™
MICROCOUPLER™
MicroFET™

MillerDrive™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR®

MicroPak™

®

PDP-SPM™ Power220® Power247® POWEREDGE®

Power-SPM™ PowerTrench®

Programmable Active Droop™

QFET<sup>®</sup> QS™

SPM<sup>®</sup>

QT Optoelectronics™ Quiet Series™ RapidConfigure™ SMART START™

STEALTH™
SuperFET™
SuperSOT™-3
SuperSOT™-6
SuperSOT™-8

SyncFET™

SYSTEM ®

The Power Franchise®

the property of the property

Ultra FRFET™ UniFET™ VCX™

\* EZSWITCH™ and FlashWriter® are trademarks of System General Corporation, used under license by Fairchild Semiconductor.

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

#### As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

## PRODUCT STATUS DEFINITIONS

## **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I32